

Notice of References Cited		Application/Control No. 10/500,401	Applicant(s)/Patent Under Reexamination OIWA ET AL.	
		Examiner SYED HASAN	Art Unit 2484	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0066113	05-2002	Utsunomiya et al.	725/146
*	B	US-6,112,010	08-2000	Koyama et al.	386/241
*	C	US-2003/0081515	05-2003	Horii et al.	369/47.16
*	D	US-2002/0159186	10-2002	Kotani, Takuya	360/75
*	E	US-2002/0097986	07-2002	Matoba et al.	386/83
*	F	US-6,292,626	09-2001	Ino et al.	386/344
*	G	US-5,414,686	05-1995	Iitsuka, Hiroyuki	369/47.29
*	H	US-2002/0044503	04-2002	Yoshida, Masayoshi	369/30.16
*	I	US-5,067,029	11-1991	Takahashi, Yohnosuke	386/225
*	J	US-7,711,564	05-2010	Levy et al.	704/270
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.